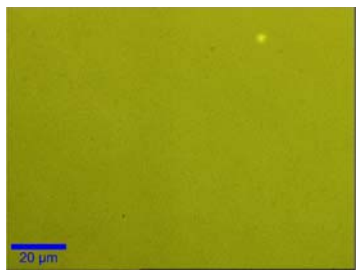
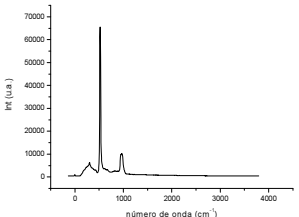
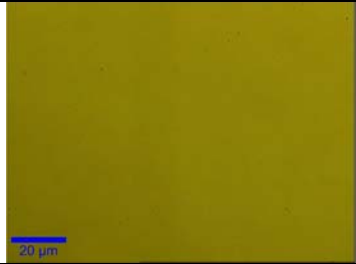
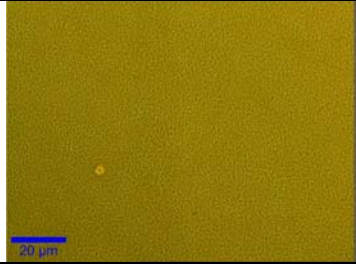
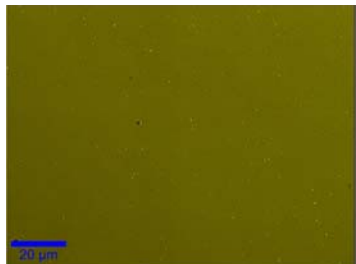
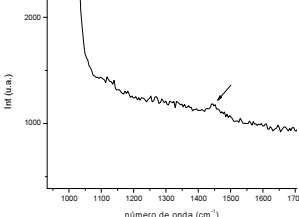


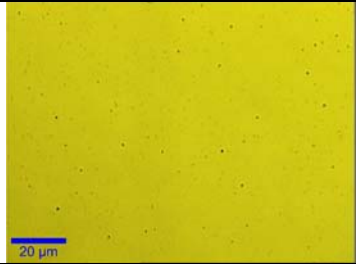
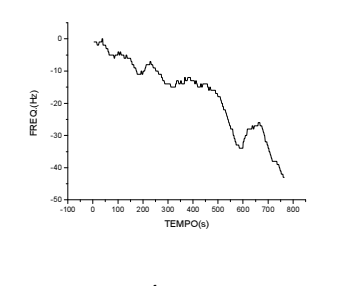
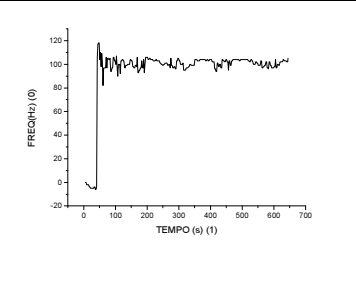
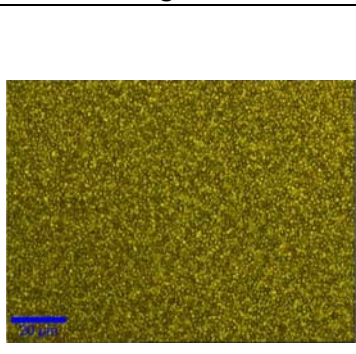
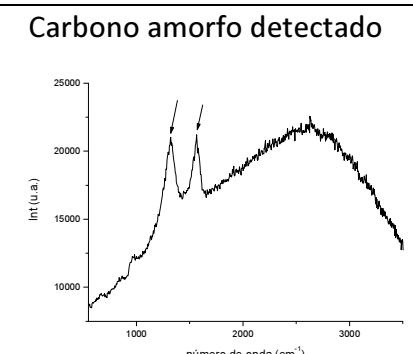
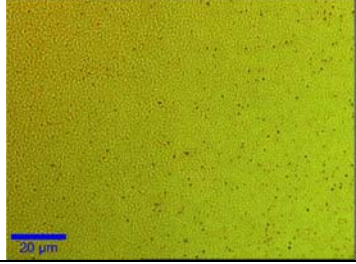
Microscopia Óptica, Raman e QCM

Modos de Deposição:

- Arranjo 0: HMDS por fora com Ar como gás de arraste;
- Arranjo 1: HMDS por dentro do plasma e sem O₂;
- Arranjo 2: HMDS por fora e O₂ também;
- Arranjo 3: HMDS por dentro do plasma e O₂ por fora.

Tabela A.3.7 – 1º Testes de modo de deposição/resultados

SUBSTRATO	NOME	MODO DEPOS.	Microscopia óptica	Microscopia Raman
Lamina Si	Deposição 1	A. 2		Só silício detectado 
Lamina Si	Deposição 2	A. 2		Só silício detectado
Lamina Si	Deposição 3	A. 2	Baixa concentração de clusters	Só silício detectado
Lamina Si	Deposição 4	A. 2		Só silício detectado, provavelmente CH ₂ no limite de detecção
Lamina Si	Deposição 5	A. 2		CH ₂ no limite de detecção 

Lamina Si	Deposição 6	A. 2		Só silício detectado
PQC	PQC 1	A. 2	 <p>água</p>	Insensível a VOCs
PQC	PQC 2	A. 2	 <p>água</p>	Insensível a VOCs
Lamina Si	Deposição 7	A. 3	  <p>Carbono amorfo detectado</p>	
Lamina Si	Deposição 8	A. 3		Só silício detectado

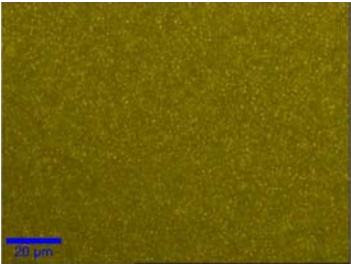
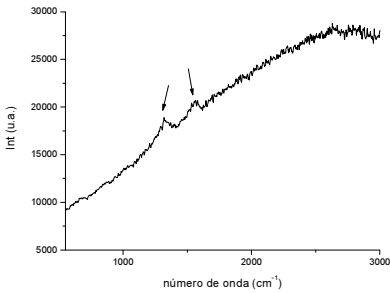
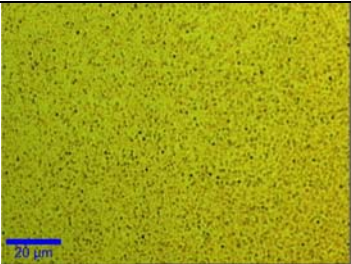
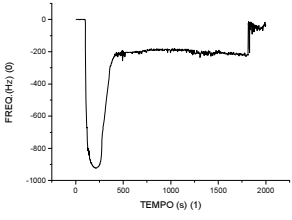
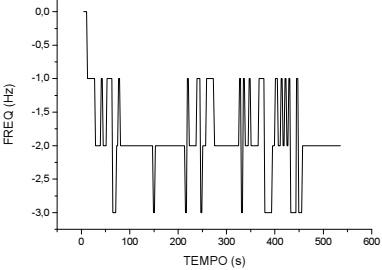
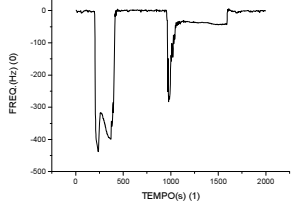
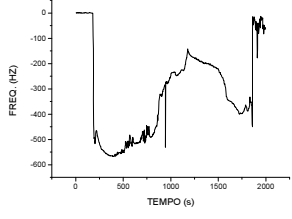
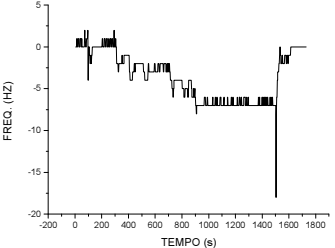
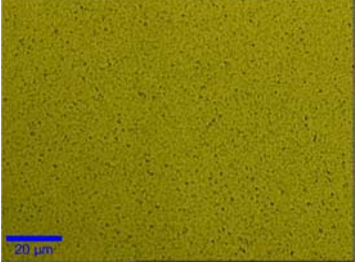
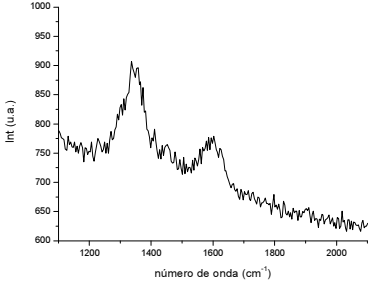
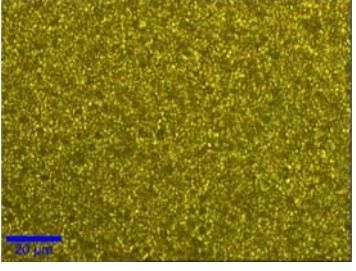
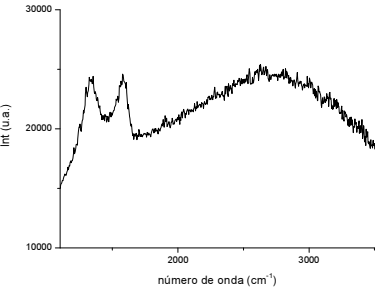
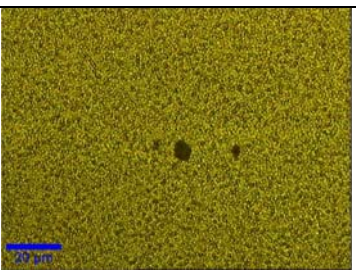
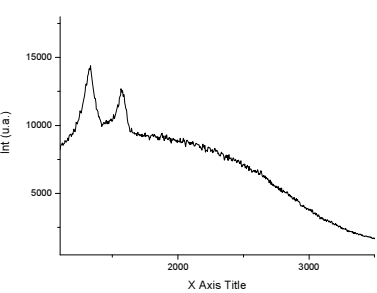
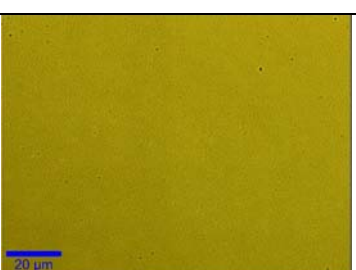
Vidro	Deposição 9	A. 3		<p>Carbono amorfo detectado</p> 
Vidro	Deposição 10	A. 3		<p>Só silício detectado</p>
PQC	PQC 3	A. 3	 <p>água</p>	 <p>Insensível a VOCs</p>
PQC	PQC 4	A. 1	 <p>água</p>	<p>Insensível a VOCs</p>
	PQC exposto		 <p>água</p>	 <p>VOCs</p>

Tabela A.3.8 – 2º Testes de modo de deposição/resultados

SUBSTRATO	NOME	MODO DEPOS.	Microscopia óptica	Microscopia Raman
Lamina Si	1	A. 1		<p>Carbono amorfo detectado</p> 
Lamina Si	2	A. 1		<p>Carbono amorfo detectado</p> 
Lamina Si	3	A. 1		<p>Carbono amorfo detectado</p> 
Lamina Si	4	A. 1		<p>Só silício detectado</p>
Lamina Si	5	A. 1	Baixa concentração de clusters	Só silício detectado
Lamina Si	6	A. 2	Baixa concentração de clusters	Só silício detectado